

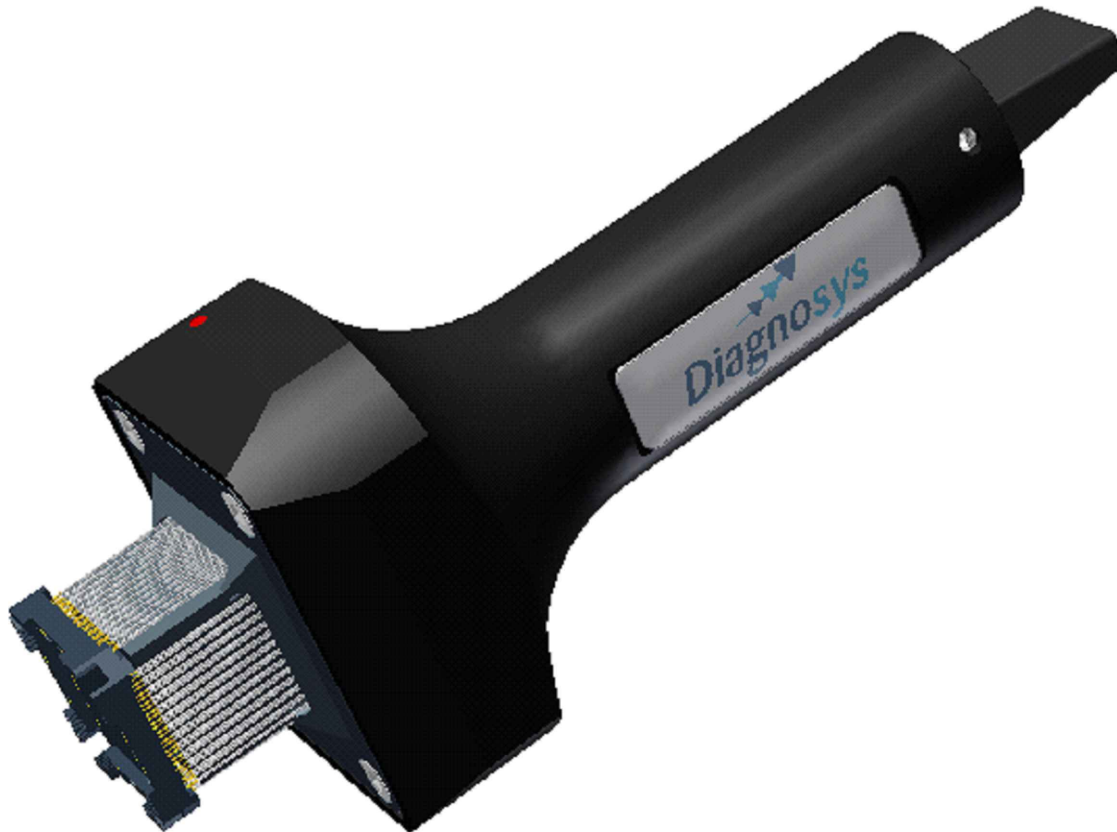
Introduction

This Test Interface is a hand held test clip, designed to probe simultaneously the leads of an assembled IC. Terminated with five 25 way male "D" type connectors, the interface makes temporary electrical contact with the leads of the device, in a two step action:

- the interface is positioned over the device to be tested (Lining it up with the body of the device and the leads).
- by pushing the handle further, the high-performance microprobes will reach the leads of the device and make electrical contact.

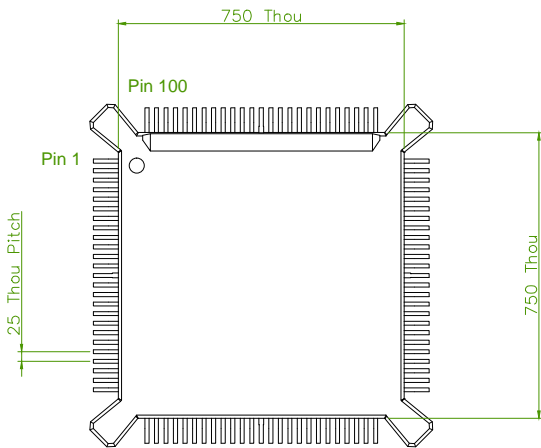
Features

- achieves the best combination of reliability, repeatability, serviceability and user-friendliness;
- high contact pressure at probe tip, for repeatable and reliable contact;
- high reliability and long life interchangeable microprobes;
- sweeping action gold plated contacts, for reliable contact and low ohmic resistance of interconnections;
- high current rating (for single channel, in ambient air with 70°F [20°C]) : 1.5A
- impact, solvent and temperature resistant plastics, with low friction;
- wide range of operating temperatures (commercial): [0°C to +70°C]
- clear markings on the body, indicating Pin 1 of IC being tested, to prevent probing the wrong way round;
- packaged in a hard wearing, high resistance to damage Polypropylene case with foam insets, the Test Interface can withstand high impact in transit.
- case can be used for safe storage when the Test Interface is not in use, and subsequent transport.
- very flexible cable (military quality harnessing) with low friction, high performance TFE TEFLON insulated wires (MIL-W-16878E Type E, UL1213);

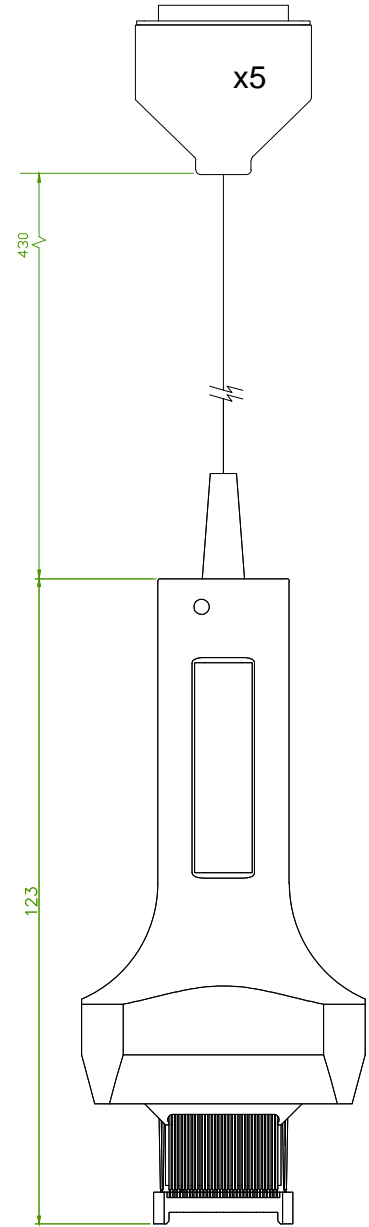
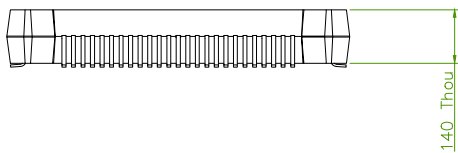


Specification

- It will accommodate a 100Pin BQFP, 25 Thou Pitch, LxWxH: 750Thou x 750Thou x 140Thou;
- Maximum number of interconnections (channels): 100
- Current rating, with all contacts loaded (maximum continuous current, non inductive): 0.5A /channel;
- Contact resistance (average): 80 mΩ /channel;
- Insulation resistance: 5MΩ Min.
- Volume resistivity of plastic parts: 10¹⁵ Ω-cm @ 50%RH.
- Fatigue life of probes: Min. 1,000,000 cycles at normal working distance;
- Working distance (normal stroke): 1.3mm;
- Microprobe force at point of contact (normal stroke): 0.3N



- NOTES**
- 1) All dimensions in mm, unless otherwise specified.
 - 2) Pin 1 of IC marked in red on probe body.



Connections Table

IC Pin	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21	22	23	24	25
Channel	97	73	99	77	103	81	102	80	107	76	108	82	98	85	120	90	110	94	111	92	112	89	115	93	119
IC Pin	26	27	28	29	30	31	32	33	34	35	36	37	38	39	40	41	42	43	44	45	46	47	48	49	50
Channel	117	96	113	86	116	87	118	95	114	91	109	88	16	68	19	65	23	69	21	70	17	66	20	61	22
IC Pin	51	52	53	54	55	56	57	58	59	60	61	62	63	64	65	66	67	68	69	70	71	72	73	74	75
Channel	47	71	43	67	40	64	39	63	38	62	48	72	26	50	36	60	35	59	30	54	31	55	27	51	10
IC Pin	76	77	78	79	80	81	82	83	84	85	86	87	88	89	90	91	92	93	94	95	96	97	98	99	100
Channel	4	58	8	52	9	56	5	49	1	53	3	57	7	78	6	79	106	75	100	83	104	84	105	74	101

Maintenance

The Test Interface Head is maintenance free. The microprobes are self-cleaning. Immersion in water or contact between microprobes and any liquids should be avoided, as this could severely reduce the working life of microprobes.

Contamination is the primary cause of probe contact problems. This is generally caused by flux left as a residue on circuit boards. Other probe contaminants such as dust, fluff, oil and grime can also cause problems in other areas. Light brushing of the tips of the probes with nylon, bristle or soft metal brushes will dislodge most contaminants.